

Analysis and Evaluation of

Sampled Imaging Systems

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Analysis and Evaluation of
**Sampled
Imaging
Systems**

**Richard H. Vollmerhausen
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Ronald G. Driggers**

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Introduction to the Series

Since its inception in 1989, the Tutorial Texts (TT) series has grown to more than 85 titles covering many diverse fields of science and engineering. The initial idea for the series was to make material presented in SPIE short courses available to those who could not attend and to provide a reference text for those who could. Thus, many of the texts in this series are generated by augmenting course notes with descriptive text that further illuminates the subject. In this way, the TT becomes an excellent stand-alone reference that finds a much wider audience than only short course attendees.

Tutorial Texts have grown in popularity and in the scope of material covered since 1989. They no longer necessarily stem from short courses; rather, they are often generated by experts in the field. They are popular because they provide a ready reference to those wishing to learn about emerging technologies or the latest information within their field. The topics within the series have grown from the initial areas of geometrical optics, optical detectors, and image processing to include the emerging fields of nanotechnology, biomedical optics, fiber optics, and laser technologies. Authors contributing to the TT series are instructed to provide introductory material so that those new to the field may use the book as a starting point to get a basic grasp of the material. It is hoped that some readers may develop sufficient interest to take a short course by the author or pursue further research in more advanced books to delve deeper into the subject.

The books in this series are distinguished from other technical monographs and textbooks in the way in which the material is presented. In keeping with the tutorial nature of the series, there is an emphasis on the use of graphical and illustrative material to better elucidate basic and advanced concepts. There is also heavy use of tabular reference data and numerous examples to further explain the concepts presented. The publishing time for the books is kept to a minimum so that the books will be as timely and up-to-date as possible. Furthermore, these introductory books are competitively priced compared to more traditional books on the same subject.

When a proposal for a text is received, each proposal is evaluated to determine the relevance of the proposed topic. This initial reviewing process has been very helpful to authors in identifying, early in the writing process, the need for additional material or other changes in approach that would serve to strengthen the text. Once a manuscript is completed, it is peer reviewed to ensure that chapters communicate accurately the essential ingredients of the science and technologies under discussion.

It is my goal to maintain the style and quality of books in the series and to further expand the topic areas to include new emerging fields as they become of interest to our reading audience.

*James A. Harrington
Rutgers University*

Contents

Preface	xi
Acronyms and Abbreviations	xiii

Part I Analysis of Sampled Imaging Systems

Chapter 1 The Sampling Process	3
1.1 Description of a Sampled Imager	3
1.2 Description of the Sampling Process	6
1.3 Linearity and Shift Invariance	9
1.4 Signal Reconstruction	13
1.5 Three Ways of Viewing the Sampling Process	15
1.5.1 The displayed image as the sum of its parts	16
1.5.2 The display as a filter of the image samples	18
1.5.3 The display as a filter of the sampled image	20
1.6 The Sampling Theorem	24
1.6.1 Theory	24
1.6.2 Example	26
1.6.3 Discussion	29
Bibliography	29
Chapter 2 Fourier Integral Representation of an Optical Image	31
2.1 Linear Shift-Invariant Optical Systems	31
2.2 Equivalence of Spatial and Frequency Domain Filters	34
2.3 Reducing LSI Imager Analysis to One Dimension	36
2.4 Perspectives on One-Dimensional Analysis	42
2.5 Imager Modulation Transfer Functions	45
2.5.1 Imager components	45
2.5.2 Line-of-sight jitter	47
2.5.2.1 Reduction of line-of-sight jitter by eye tracking	50
2.5.2.2 Effect of temporal sampling on line-of-sight jitter	52
2.5.3 Electronic stabilization	53
2.5.4 Motion blur	55

2.5.5	Field replication.....	56
2.5.6	Analog electronic filters	56
2.5.7	Display MTF	57
	Bibliography.....	59
Chapter 3	Sampled Imager Response Function.....	61
3.1	Fourier Transform of a Sampled Image.....	63
3.2	The Sampled Imager Response Function	67
3.3	Examples of Sampled Imager Response Functions.....	69
3.3.1	Example 1: The pictures of Lena in Chapter 1	69
3.3.2	Example 2: Effect of changing sample rate.....	71
3.3.3	Example 3: Midwave thermal imager	79
3.3.4	Example 4: Two-dimensional SIR example.....	81
	Bibliography.....	85
Chapter 4	Sampled Imager Optimization	87
4.1	Interpolation Implementation	89
	Bibliography.....	97
Chapter 5	Interlace and Dither	99
5.1	Sampling Improvement with Static Scene.....	102
5.2	Resolution and Sensitivity	107
5.3	Effect of Scene-to-Sensor Motion	110
	Bibliography.....	112
Part II	Evaluating the Performance of Electro-Optical Imagers	
Chapter 6	Quantifying Visual Task Performance	115
6.1	Specifying and Evaluating Field Performance	118
6.2	Factors That Influence Target Identification	120
6.3	Measuring Target Signatures.....	121
6.4	Experimental Procedure	122
6.5	Field Test Procedure.....	125
6.6	Test Sets Other Than Tactical Vehicles.....	127
6.7	Field Testing Using Bar Targets.....	129
Chapter 7	Evaluating Imager Resolution	131
7.1	Imager Evaluation Procedure	132
7.2	Modeling Gain, Level, and the User Interface	134
7.3	Observer Vision.....	138
7.4	Predicting Probability of Identification	143

7.4.1	Comparing experimental data to model predictions.....	145
7.5	Test Sets Other Than Tactical Vehicles.....	146
	Bibliography.....	147
Chapter 8	Quantifying the Effect of Aliasing on Visual Task Performance.....	149
8.1	Model Treatment of Spatial Noise.....	150
8.2	Treatment of Temporal Noise in Detectivity Versus Photon-Counting Models.....	152
8.3	Relating Target and Imager Coordinate Systems.....	155
8.4	Spatial Scaling of Aliasing Noise.....	161
	Bibliography.....	163
Chapter 9	Thermal Imager Topics	165
9.1	Effective Blackbody Temperature.....	168
9.2	Signal and Noise in the Detectivity Model.....	172
9.3	Thermal Imager Contrast Threshold Function	175
9.4	Adding Aliasing Noise	177
9.5	Predicting Range Performance	179
9.6	Modeling Contrast Enhancement and Boost	180
9.7	Minimum Resolvable Temperature.....	182
9.7.1	Predicting minimum resolvable temperature.....	183
9.7.2	Predicting sampled imager minimum resolvable temperature.....	187
9.7.3	Improving the minimum resolvable temperature procedure.....	190
	Bibliography.....	191
Chapter 10	Imagers of Reflected Light.....	193
10.1	Calculating Target Set Contrast.....	193
10.2	System Contrast Threshold Function	196
10.2.1	Interlace.....	200
10.2.2	Snapshot and frame integration.....	201
10.3	Predicting Range Performance	202
	Bibliography.....	203
Part III	Applications	
Chapter 11	Computer Programs and Application Data	207
11.1	Optics Modulation Transfer Function	208
11.1.1	Thermal imagers.....	208
11.1.2	Imagers of reflected light.....	211
11.2	Display Modulation Transfer Function	213

11.2.1	Cathode ray tubes	213
11.2.2	Liquid crystal displays.....	216
11.2.3	Display interface format	218
11.3	Atmospheric Transmission and Turbulence	218
11.3.1	Atmosphere in the reflective model.....	219
11.3.2	Atmosphere in the thermal model	221
11.3.3	Atmospheric turbulence.....	223
11.4	Detector Calculations	223
11.4.1	Detector noise.....	223
11.4.2	Detector modulation transfer function.....	226
11.5	Computer Program Description.....	227
11.6	Imager Analysis Using the Programs	235
11.6.1	Imager resolution.....	235
11.6.2	System contrast threshold function.....	236
11.6.3	Range plots	237
	References	240
	Bibliography.....	240
Chapter 12 Infrared Focal Plane Arrays		241
12.1	Photon Detector Infrared Focal Plane Arrays.....	241
12.1.1	Photon detector basic principles	241
12.1.2	Readout integrated circuit.....	246
12.1.3	Photon detector dark current	247
12.2	IR FPA Performance Characterization	251
12.2.1	Responsivity and detectivity background-limit performance.....	252
12.2.2	Flux-based signal-to-noise ratio	255
12.3	Commonly Available Photon Detector FPAs.....	258
12.3.1	Indium antimonide (InSb) detectors	258
12.3.2	Quantum well infrared photoconductor (QWIP) detectors.....	261
12.3.3	Mercury cadmium telluride (HgCdTe) detectors	264
12.4	Uncooled Detectors	269
12.4.1	Introduction	269
12.4.2	Signal-to-noise ratio and performance limits	271
12.4.3	Typical uncooled detectors.....	273
	References	274
Appendix Observer Vision Model.....		277
A.1	Contrast Threshold Function	277
A.2	Engineering Model of the Eye.....	278
	References	282
Index.....		285

Preface

This tutorial is written for the design engineer or system analyst interested in quantifying the performance of electro-optical imagers. Advancing technology in detector arrays, flat panel displays, and digital image processing provide new opportunities to expand imaging applications and enhance system performance. Technical managers and design engineers are faced with evaluating the cost, weight, and performance of an ever-expanding selection of technology options. This book provides the theory and procedures for performance assessment.

This text supersedes *Analysis of Sampled Imaging Systems*, which was published by SPIE Press in 2000. Part I updates the earlier work. Part II discusses performance evaluation of electro-optical imagers. Part III provides computer programs and up-to-date information on detector arrays, optics, and display options. This book provides the theory, procedures, and information needed to evaluate and compare the performance of available imaging technologies.

Our prior work *Analysis of Sampled Imaging Systems* focused on the mathematical formulism needed to analyze sampled imagery. That book described the sampled imager response (SIR) function. SIR quantified sampled imager aliasing as well as the system transfer response. Fourier transform theory was used to describe and quantify sampling artifacts such as display raster, blocky images, and the loss or alteration of image detail due to aliasing.

However, the metrics provided by the earlier book were “rules of thumb.” Sampled imager design rules were based on experience and experimentation. No theory existed to quantify the effect of aliasing on visual task performance. The earlier work provided guidance on how to optimize sampled imagers by minimizing aliasing. *Analysis of Sampled Imaging Systems* did not provide a procedure to quantify the impact of aliasing on performance.

In the intervening years since the first book, we have discovered that the effect of aliasing on targeting performance is predictable by treating aliasing as noise. This book presents a resolution metric that predicts the effect of imager blur, noise, and sampling on the probability of correctly identifying targets. This new publication includes quantitative procedures for evaluating target acquisition performance.

Part I of this book includes all of the pertinent material from *Analysis of Sampled Imaging Systems*. The first five chapters remain substantially the same as the previous work. These chapters introduce sampling concepts and describe the differences between shift-variant and shift-invariant systems. Chapter 2 on Fourier optics is extensively rewritten. The errors associated with assuming

separability in Cartesian coordinates are discussed, and examples are provided. The blurs associated with vibration and electronic stabilization are described. In Chapter 3, additional examples are added to better describe the SIR function. The focus of Chapters 1 through 5 remains the same, however. These chapters provide the mathematical tools needed to analyze sampled imagers.

Part II of this new book includes Chapters 6 through 10. This new material describes electro-optical imager evaluation. Chapter 6 describes target identification experiments. These experiments quantify visual task performance. Chapter 7 describes a resolution metric that predicts the probability of identifying targets. Chapter 7 also discusses the relationship between imager resolution and field performance. Chapter 8 explains aliasing as noise theory. For some years, we have known how to predict the effect of noise on target acquisition. Aliasing as noise theory predicts the effect of aliasing on target acquisition. Chapters 9 and 10 provide details on analyzing thermal imagers and imagers of reflected light, respectively.

Part III provides computer programs that implement the theory. These programs calculate the resolution of thermal and reflected light imagers. The programs are used to evaluate expected target acquisition performance and to compare imagers and assess the benefit or penalty of design changes.

Information is also provided to help make realistic assessments of imager performance. The book discusses optical performance and provides the characteristics of typical, good, and ideal lens systems. The book also contains information on a variety of display formats and interfaces, as well as detailed information on available focal plane arrays (FPAs). The information is presented in written form and is also coupled to the computer programs.

Particular emphasis is placed on theory and practice for the wide variety of available infrared FPAs. Technologies represented include InSb, HgCdTe, QWIP, and uncooled thermal arrays. Information is provided on the quantum efficiency, blur, crosstalk, and noise characteristics of each technology. The detector and array dimensions of available FPAs are provided. The availability of current information on optics, display, and FPA subassemblies allows the model user to make quick and realistic performance assessments of electro-optical imager designs.

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February 2010

Acronyms and Abbreviations

2afc	two alternative forced choice
A	ampere
Å	angstrom
AAN	aliasing as noise
AR	antireflection
A/W	units (amperes/watt) for spectral current responsivity
BDI	buffered direction injection
BLIP	background-limited photoconductor
CCD	charge-coupled device
CMOS	complementary metal-oxide semiconductor
CRT	cathode ray tube
CSF	contrast sensitivity function
CTF	contrast threshold function
CTIA	capacitive transimpedance amplifier
DC	direct current
DI	direct injection
DLHJ	double-layer heterojunction
<i>erf</i>	error function
E field	electric field
E-stab	electronic stabilization
ezoom	electron zoom
FF	fill factor
FOV	field of view
FPA	focal plane array
FPN	fixed pattern noise
FWHM	full width at half maximum
HDTV	high-definition television
HgCdTe	mercury cadmium telluride
HUD	head-up display
IFOV	instantaneous field of view
InSb	indium antimonide
IR	infrared
LACE	local-area contrast enhancement
LCD	liquid crystal display
LOS	line of sight
LSI	linear and shift invariant

LWIR	long-wave infrared
MHz	megahertz
MKS	meter-kilogram-second
MRT	minimum resolvable temperature
MTF	modulation transfer function
MWIR	midwave infrared
NEP	noise equivalent power
NETD	noise equivalent temperature difference
NIR	near infrared
NUC	nonuniformity correction
OTF	optical transfer function
Pf	picofarad
PID	probability of correct identification
psf	point spread function
PSQ	square of the Pearson's coefficient
PV	photovoltaic
QE	quantum efficiency
QWIP	quantum well infrared photoconductor
RC	resistor-capacitor
rms	root mean square
ROIC	readout integrated circuit
RSS	square root of the sum of squares
SGR	sky-to-ground ratio
SIR	sampled imager response
SIT	system intensity transfer
SMAG	system magnification
S/N	signal-to-noise ratio
SOM	specific object model
SRH	Shockley-Read-Hall
SSD	signal spectral density
str	steradian
SWIR	short-wave infrared
TCR	temperature coefficient of resistance
tgt	target
TOD	triangle orientation discrimination
TTP	targeting task performance
UAV	unmanned aerial vehicle
VFOV	vertical field of view
W	watt
WFOV	wide field of view